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Fairchild Semiconductor FCH47N60_F133

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December 2013

FCH47N60

N-Channel SuperFET[®] MOSFET 600 V, 47 A, 70 m Ω

Features

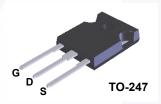
- 650 V @ T_J = 150°C
- Typ. $R_{DS(on)}$ = 58 m Ω
- Ultra Low Gate Charge (Typ. Q_g = 210 nC)
- Low Effective Output Capacitance (Typ. C_{oss(eff.)} = 420 pF)
- 100% Avalanche Tested
- · RoHS Compliant

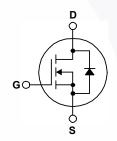
Applications

- · Solar Inverter
- AC-DC Power Supply

Description

SuperFET[®] MOSFET is Fairchild Semiconductor's first generation of high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low onresistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, dv/dt rate and higher avalanche energy. Consequently, SuperFET MOSFET is very suitable for the switching power applications such as PFC, server/telecom power, FPD TV power, ATX power and industrial power applications.





MOSFET Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol		Parameter	FCH47N60_F133	Unit
V _{DSS}	Drain to Source Voltage		600	V
	Drain Current	Continuous (T _C = 25°C)	47	
ID	Drain Current	Continuous (T _C = 100°C)	29.7	A
I _{DM}	Drain Current	Pulsed (Note 1)	141	Α
V _{GSS}	Gate to Source Voltage		±30	V
E _{AS}	Single Pulsed Avalanche Er	ergy (Note 2)	1800	mJ
I _{AR}	Avalanche Current	(Note 1)	47	Α
E _{AR}	Repetitive Avalanche Energ	y (Note 1)	41.7	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns
В	Power Dissinction	(T _C = 25°C)	417	W
P_{D}	Power Dissipation	Derate Above 25°C	3.33	W/°C
T _J , T _{STG}	Operating and Storage Tem	perature Range	-55 to +150	°C
T _L	Maximum Lead Temperature 1/8" from Case for 5 Second	<u>.</u>	300	°C

Thermal Characteristics

Symbol	Parameter	FCH47N60_F133	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.3	°C/W
$R_{\theta JA}$	Thermal Resistance, Case-to-Sink, Typ.	0.24	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	41.7	°C/W



Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FCH47N60_F133	FCH47N60	TO-247	Tube	N/A	N/A	30 units

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	eteristics					
D\/	Drain-to-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}, T_C = 25^{\circ}\text{C}$	600	-	-	V
BV _{DSS}	Drain-to-Source Breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}, T_C = 150^{\circ}\text{C}$	-	650	-	V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C	-	0.6	-	V/°C
BV _{DS}	Drain to Source Avalanche Breakdown Voltage	V _{GS} = 0 V, I _D = 47 A	-	700	-	V
	Zero Gate Voltage Drain Current	V _{DS} = 600 V, V _{GS} = 0 V	-	-	1	
IDSS	Zero Gate voltage Drain Current	V _{DS} = 480 V, T _C = 125°C	-	-	10	μΑ
I _{GSS}	Gate-to-Body Leakage Current	V _{GS} = ±30 V, V _{DS} = 0 V	-	-	±100	nA

On Characteristics

V	GS(th)	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu\text{A}$	3.0	-	5.0	V
R_{l}	DS(on)	Static Drain-to-Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 23.5 \text{ A}$		0.058	0.070	Ω
g _F	-s	Forward Transconductance	$V_{DS} = 40 \text{ V}, I_{D} = 23.5 \text{ A}$	-	40	-	S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 05.V.V 0.V	-	5900	8000	pF
C _{oss}	Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz	-	3200	4200	pF
C _{rss}	Reverse Transfer Capacitance	1 = 1.0 WH 12	-	250	-	pF
C _{oss}	Output Capacitance	V _{DS} = 480 V, V _{GS} = 0 V, f = 1.0 MHz	-	160	-	pF
C _{oss(eff.)}	Effective Output Capacitance	V _{DS} = 0 V to 400 V, V _{GS} = 0 V	-	420	-	pF

Switching Characteristics

U							
$t_{d(on)}$	Turn-On Delay			-	185	430	ns
t _r	Turn-On Rise Time	$V_{DD} = 300 \text{ V}, I_D = 47 \text{ A},$		- /	210	450	ns
t _{d(off)}	Turn-Off Delay	$V_{GS} = 10 \text{ V, R}_{G} = 25 \Omega$		-/	520	1100	ns
t _f	Turn-Off Fall Time	(No	te 4)	7-	75	160	ns
Q _{g(tot)}	Total Gate Charge at 10 V	V _{DS} = 480 V, I _D = 47 A,		/ -	210	270	nC
Q_{gs}	Gate to Source Gate Charge	V _{GS} = 10 V		-	38	-	nC
Q _{gd}	Gate to Drain "Miller" Charge	(No	te 4)	-	110	-	nC

Drain-Source Diode Characteristics

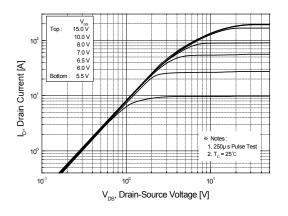
I _S	Maximum Continuous Drain-to-Source Diode Forward Current		-	-	47	Α
I _{SM}	Maximum Pulsed Drain-to-Source Diode Forward Current		-	-	141	Α
V_{SD}	Drain-to-Source Diode Forward Voltage	V _{GS} = 0 V, I _{SD} = 47 A	-	_	1.4	V
t _{rr}	Reverse-Recovery Time	$V_{GS} = 0 \text{ V, } I_{SD} = 47 \text{ A,}$ $dI_{F}/dt = 100 \text{ A/}\mu\text{s}$	-	590	-	ns
Q _{rr}	Reverse-Recovery Charge	dl _F /dt = 100 A/μs	_	25	-	μС

Notes:

- ${\it 1. Repetitive\ rating: pulse-width\ limited\ by\ maximum\ junction\ temperature.}$
- 2. I_{AS} = 18 A, V_{DD} = 50 V, R_{G} = 25 Ω , starting T_{J} = 25°C.
- 3. $I_{SD} \le 48$ A, di/dt ≤ 200 A/ μ s, $V_{DD} \le BV_{DSS}$, starting T_J = 25°C.
- 4. Essentially independent of operating temperature.



Typical Performance Characteristics



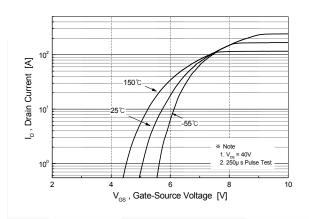


Figure 1. On-Region Characteristics

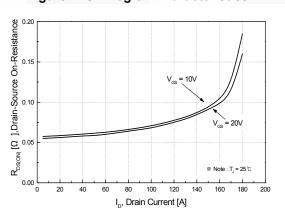


Figure 2. Transfer Characteristics

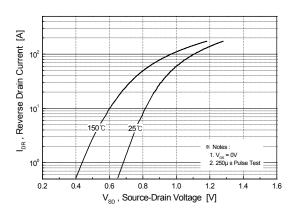


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

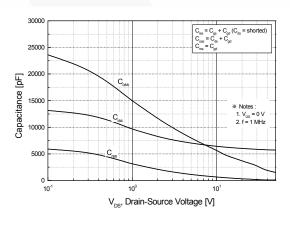


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

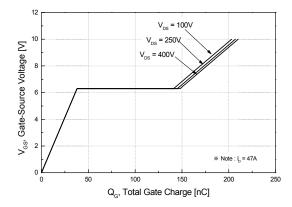
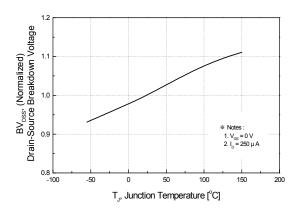


Figure 5. Capacitance Characteristics

Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)



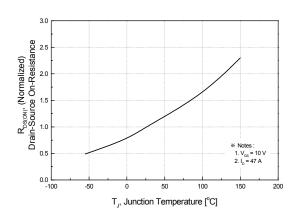
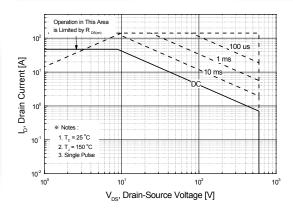


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



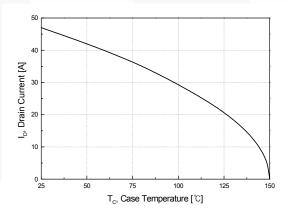


Figure 9. Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

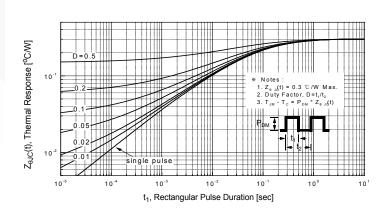


Figure 11. Transient Thermal Response Curve



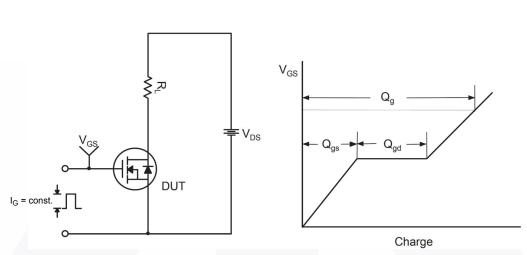


Figure 13. Gate Charge Test Circuit & Waveform

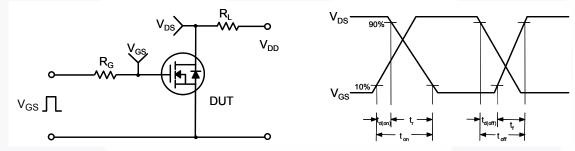


Figure 14. Resistive Switching Test Circuit & Waveforms

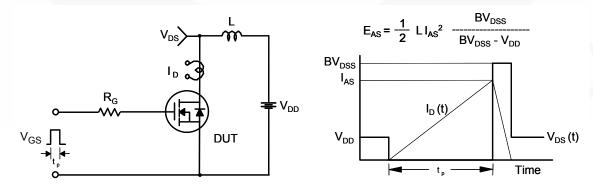


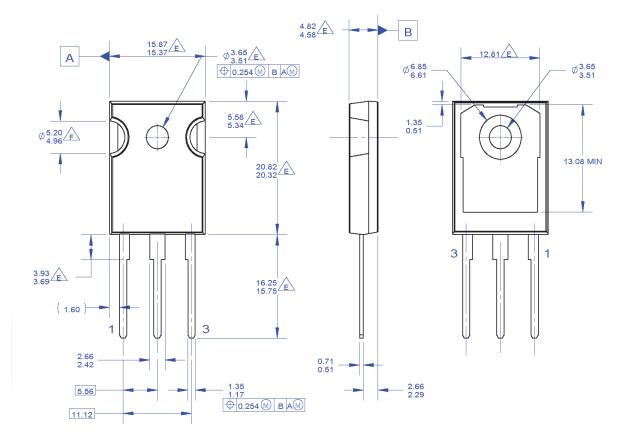
Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms



DUT I SD a Driver Same Type as DUT V_{DD} • dv/dt controlled by R_G • \mathbf{I}_{SD} controlled by pulse period Gate Pulse Width V_{GS} Gate Pulse Period 10V (Driver) \mathbf{I}_{FM} , Body Diode Forward Current ISD di/dt (DUT) I_{RM} **Body Diode Reverse Current** V_{DS} (DUT) Body Diode Recovery dv/dt V_{SD} **Body Diode** Forward Voltage Drop Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms







NOTES: UNLESS OTHERWISE SPECIFIED

- A. PACKAGE REFERENCE: JEDEC TO-247,
- ISSUE E, VARIATION AB, DATED JUNE, 2004.
 DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD
- FLASH, AND TIE BAR EXTRUSIONS.
 ALL DIMENSIONS ARE IN MILLIMETERS.
- D. DRAWING CONFORMS TO ASME Y14.5 1994

DOES NOT COMPLY JEDEC STANDARD VALUE

E NOTCH MAY BE SQUARE

DRAWING FILENAME: MKT-TO247A03_REV03

Figure 17. TO-247, Molded, 3-Lead, Jedec Variation AB

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Datasheet of FCH47N60_F133 - MOSFET N-CH 600V 47A TO-247

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No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
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